Features

- Uses CRM(CQ) advanced SkyMOS5 technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent Q_gx$R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria

Applications

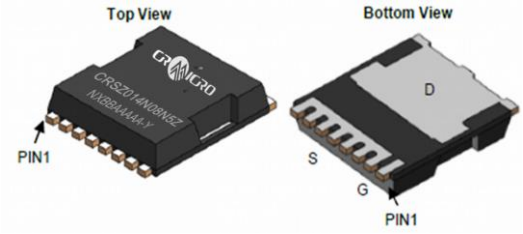
- Motor control and drive
- Battery management System
- UPS (Uninterrupible Power Supplies)

Product Summary

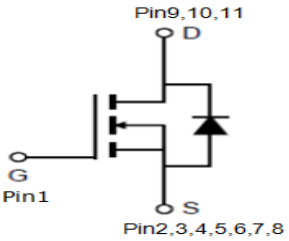
V_{DS}	85V
$R_{DS(on).typ}$	1.1mΩ
I_D	310A

100% DVDS Tested

100% Avalanche Tested



CRSZ014N08N5Z



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRSZ014N08N5Z	CRSZ014N08N5Z	TOLL	Tape&Reel	N/A	N/A	2000pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	85	V
Continuous drain current			
T_C = 25 ℃ (Silicon limit)	I_D	350	A
T_C = 100 ℃ (Silicon limit)		219	
Pulsed drain current (T_C = 25 ℃, t_p limited by T_{jmax})	$I_{D\,pulse}$	1240	A
Avalanche energy, single pulse (I_D = 85A, Rg=25Ω)[1]	E_{AS}	1819	mJ
Gate-Source voltage	V_{GS}	±20	V
Power dissipation (T_C = 25 ℃)	P_{tot}	298	W
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	℃

※. Notes:

1.EAS is tested at starting Tj = 25℃, L = 0.5mH, IAS =85A, VGS = 10V.

Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R_{thJC}	0.42	℃/W
Thermal resistance, junction – ambient(min. footprint)	R_{thJA}	41	

Electrical Characteristic (at Tj = 25 ℃, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Static Characteristic						
Drain-source breakdown voltage	BV_{DSS}	85	-	-	V	V_{GS}=0V, I_D=250uA
		85	-	-	V	V_{GS}=0V, I_D=1mA
Gate threshold voltage	$V_{GS(th)}$	2.0	3.0	4.0	V	V_{DS}=V_{GS},I_D=250uA
Zero gate voltage drain current	I_{DSS}	-	-	1	μA	V_{DS}=80V,V_{GS}=0V T_j=25 ℃
		-	-	100		T_j=125 ℃
Gate-source leakage current	I_{GSS}	0	-	±100	nA	V_{GS}= ±20V,V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	-	1.1	1.4	mΩ	VGS=10V, ID=90A
Transconductance	g_{fs}	-	227	-	S	V_{DS}=5V, I_D=90A
Dynamic Characteristic						
Input Capacitance	C_{iss}	-	14674	-	pF	V_{GS}=0V, V_{DS}=60V, f=1MHz
Output Capacitance	C_{oss}	-	1713	-		
Reverse Transfer Capacitance	C_{rss}	-	40	-		
Gate Total Charge	Q_G	-	221.4	-	nC	V_{GS}=10V, V_{DS}=40V, I_D=90A
Gate-Source charge	Q_{gs}	-	94.9	-		
Gate-Drain charge	Q_{gd}	-	37.2	-		
Turn-on delay time	$t_{d(on)}$	-	50.7	-	ns	V_{GS}=10V, V_{DD}=40V, R_{G_ext}=3.0Ω
Rise time	t_r	-	85.9	-		
Turn-off delay time	$t_{d(off)}$	-	109.8	-		
Fall time	t_f	-	37.2	-		
Gate resistance	R_G	-	2.1	-	Ω	V_{GS}=0V, V_{DS}=0V, f=1MHz

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	-	0.84	1.4	V	V_{GS}=0V,I_{SD}=90A
Body Diode Reverse Recovery Time	t_{rr}	-	85.5	-	ns	I_F=90A,dI/dt=100A/μs
Body Diode Reverse Recovery Charge	Q_{rr}	-	202	-	nC	

Typical Performance Characteristics

Fig 1: Output Characteristics

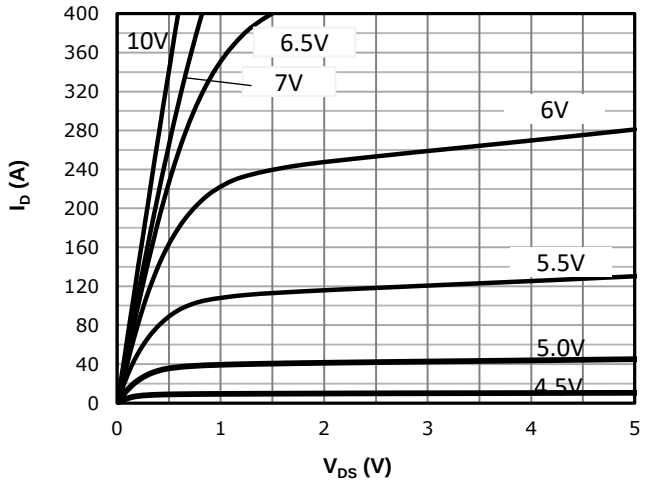


Fig 2: Transfer Characteristics

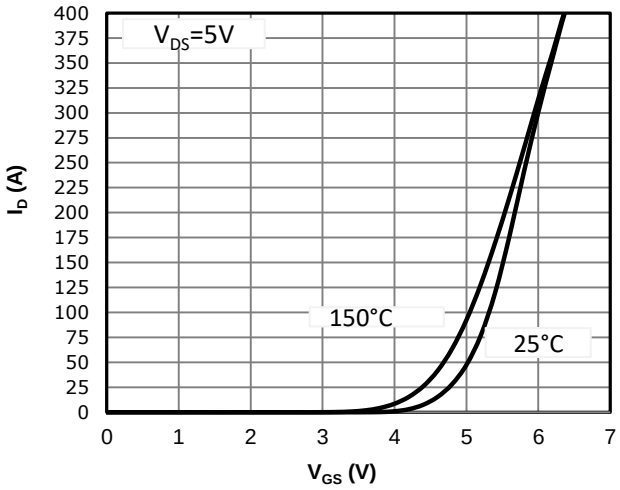


Fig 3: Rds(on) vs Drain Current and Gate Voltage

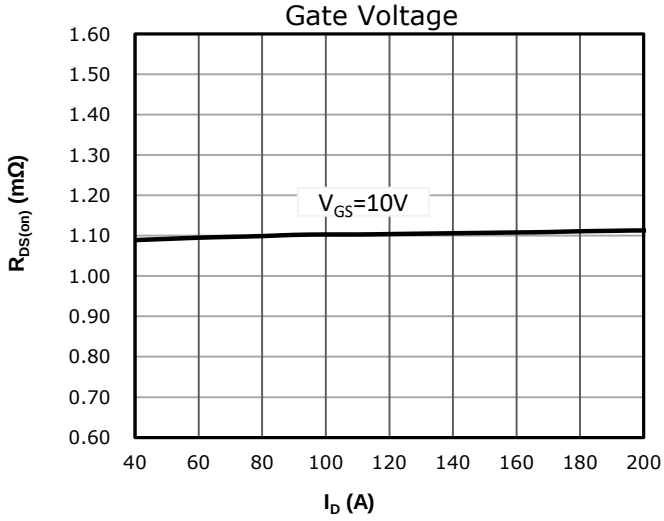


Fig 4: Rds(on) vs Gate Voltage

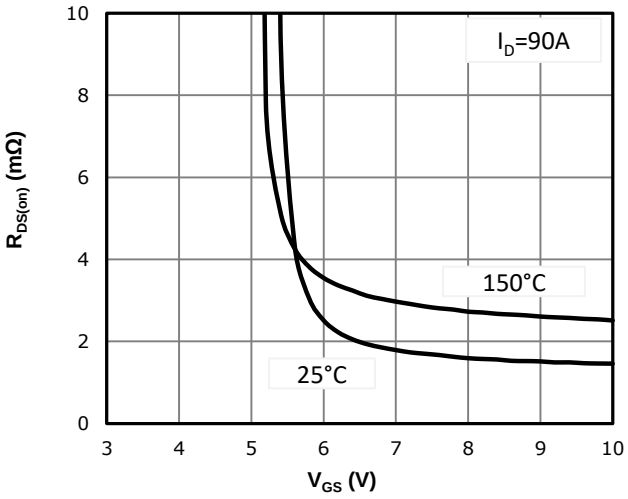


Fig 5: Rds(on) vs. Temperature

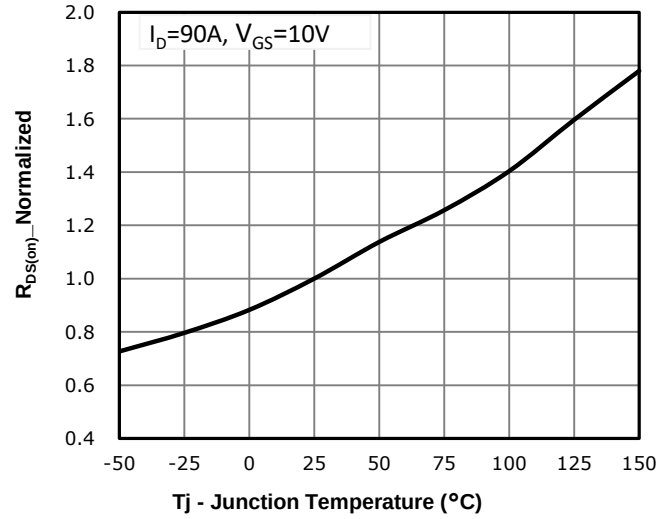


Fig 6: Vgs(th) vs. Temperature

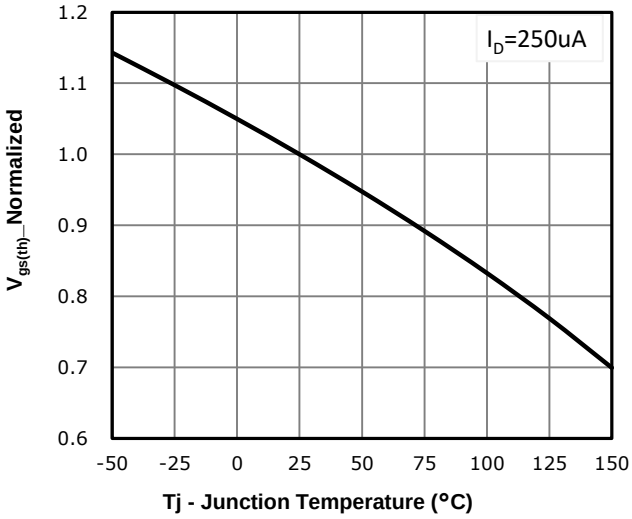


Fig 7: BVdss vs. Temperature

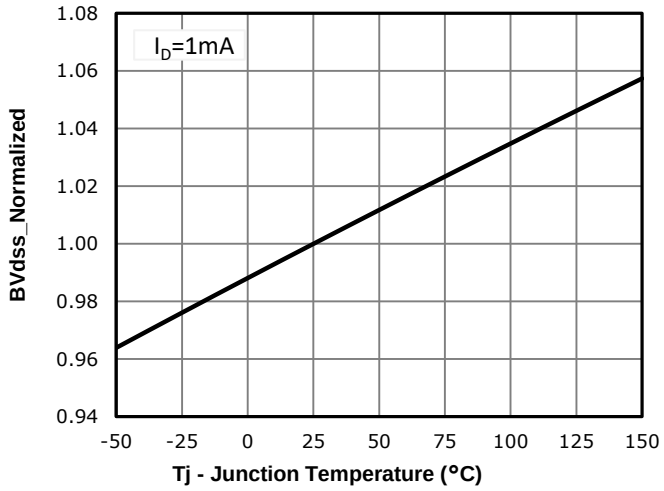


Fig 8: Capacitance Characteristics

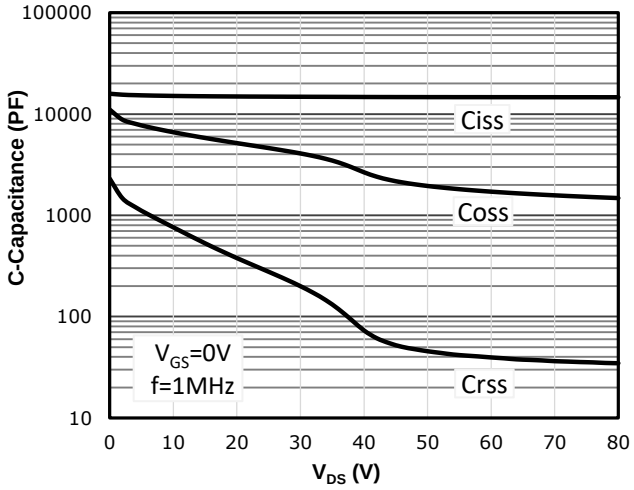


Fig 9: Gate Charge Characteristics

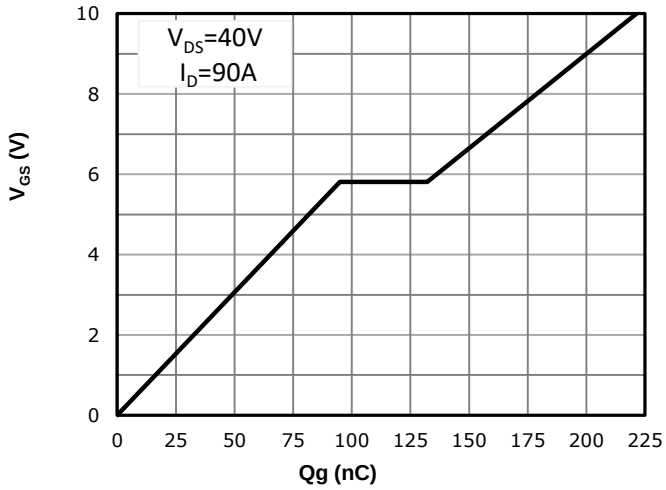


Fig 10: Body-diode Forward Characteristics

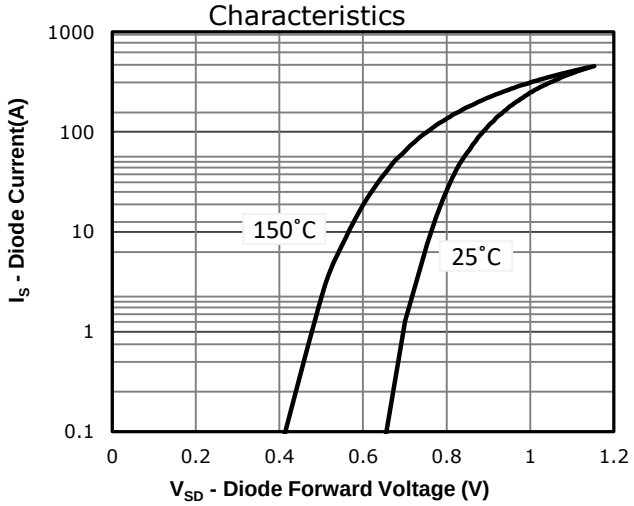


Fig 11: Power Dissipation

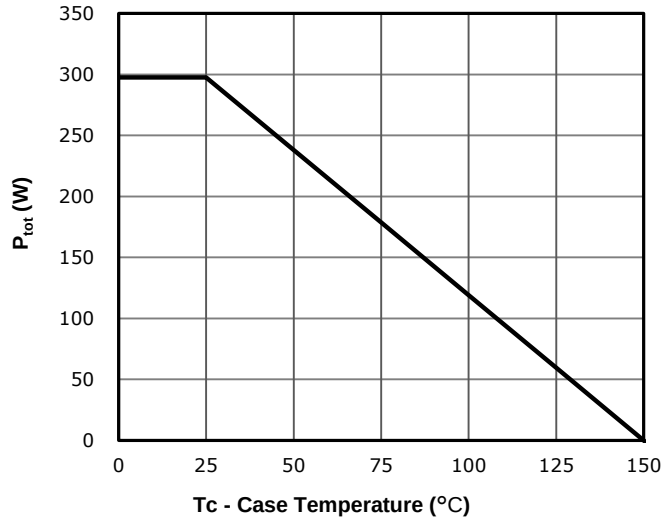


Fig 12: Drain Current Derating

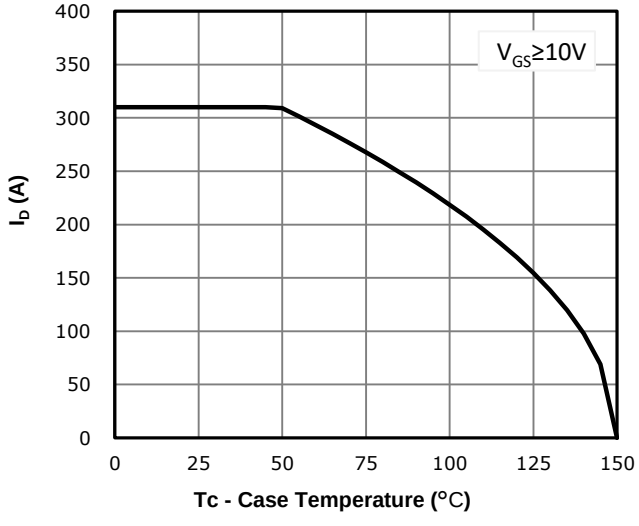


Fig 13: Safe Operating Area

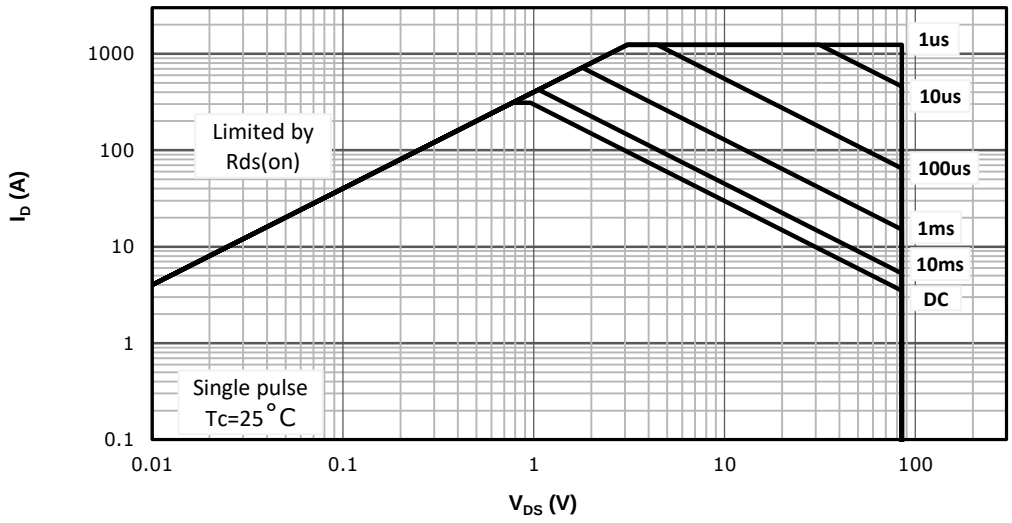
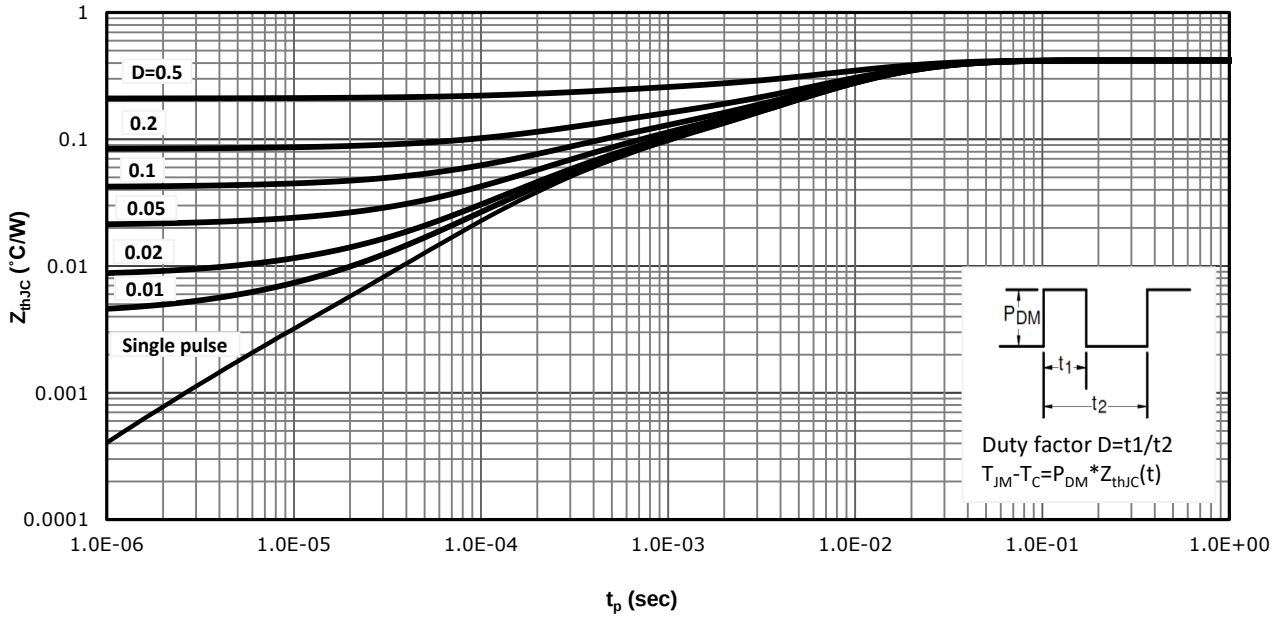
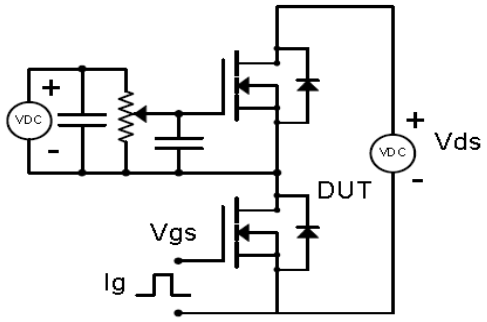


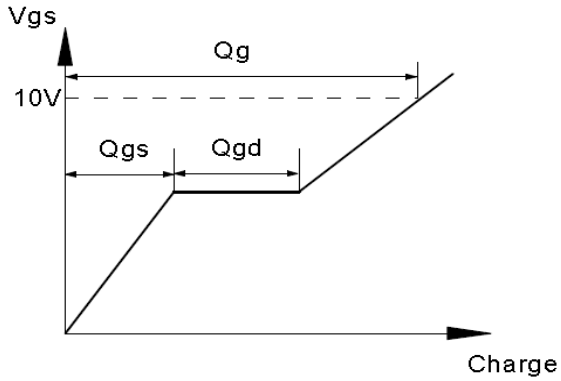
Fig 14: Max. Transient Thermal Impedance



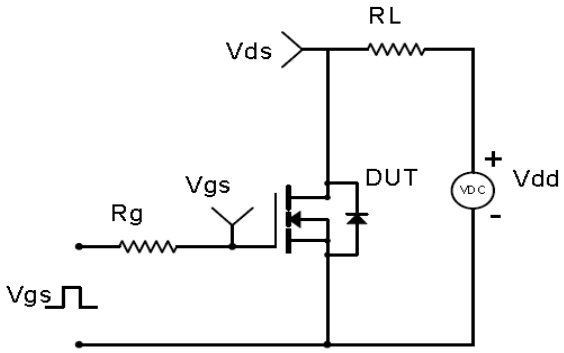
Test Circuit & Waveform

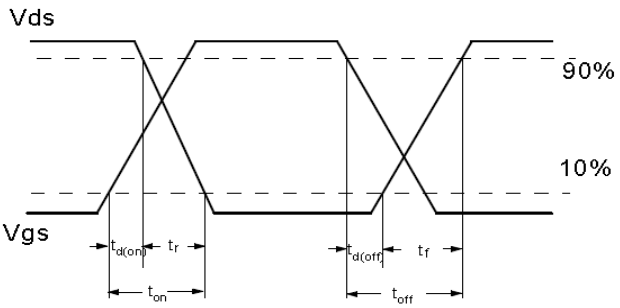
Gate Charge Test Circuit & Waveform



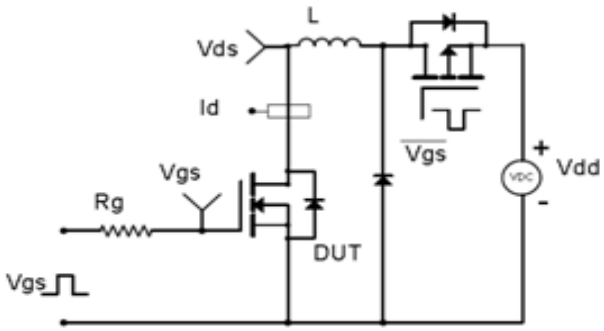


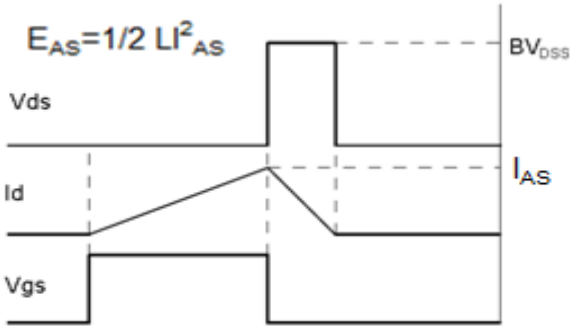
Resistive Switching Test Circuit & Waveforms



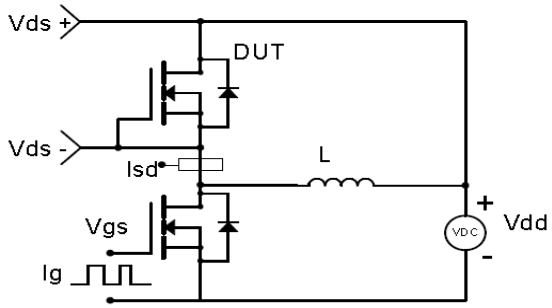


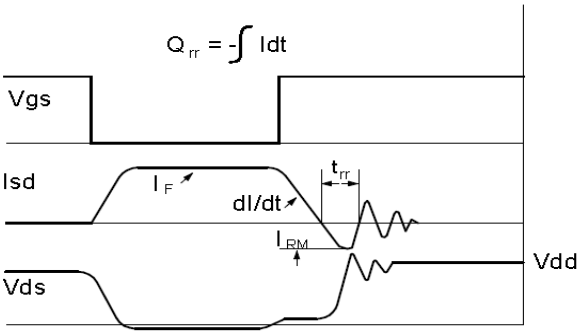
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



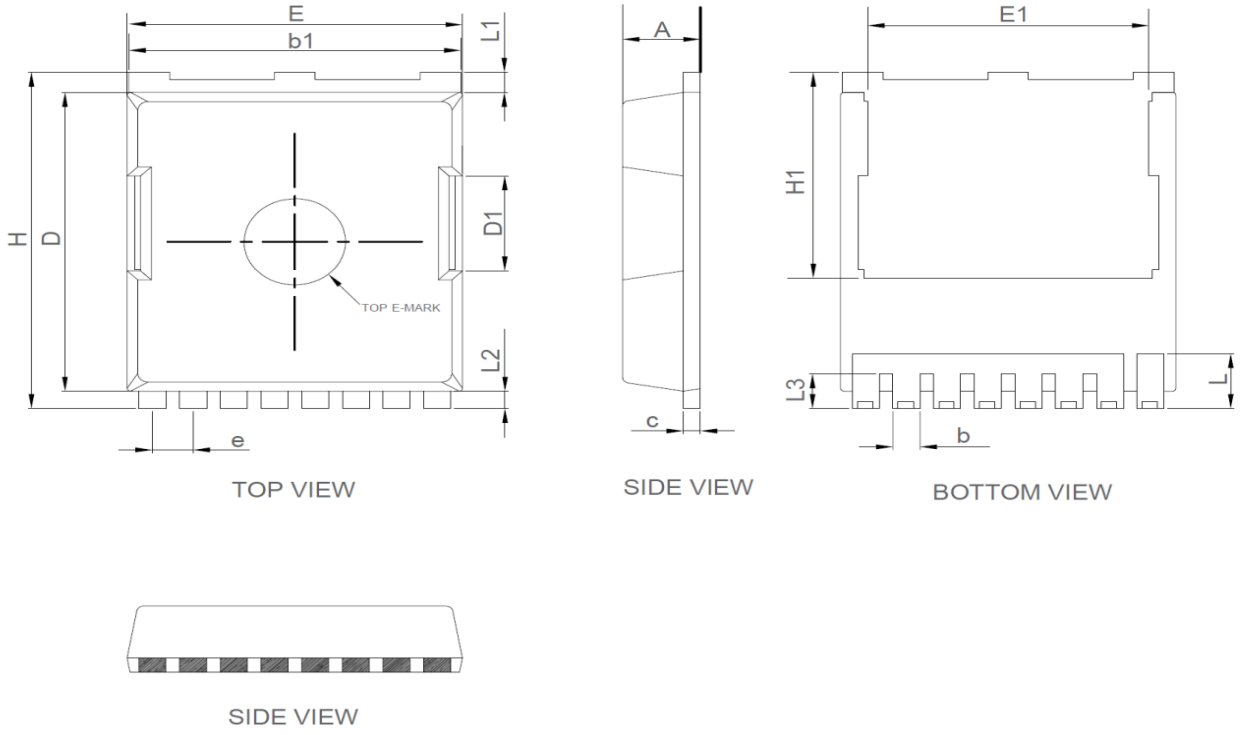


Diode Recovery Test Circuit & Waveforms





Package Outline: TOLL



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.15	2.45	0.085	0.096
b	0.60	0.90	0.024	0.035
b1	9.65	9.95	0.380	0.392
c	0.35	0.65	0.014	0.026
D	10.18	10.70	0.401	0.421
D1	3.15	3.45	0.124	0.136
E	9.70	10.10	0.382	0.398
E1	7.35	8.45	0.289	0.333
e	1.10	1.30	0.043	0.051
H	11.45	11.95	0.451	0.470
H1	6.55	7.50	0.258	0.295
L	1.35	2.10	0.053	0.083
L1	0.50	0.90	0.020	0.035
L2	0.40	0.80	0.016	0.031
L3	0.95	1.35	0.037	0.053

Marking



NOTE:
NXBBAAAAA-Y

N	—Wire Bond code
X	—Assembly location code
BB	—Fab code
AAAAA	—Lot code
Y	—Bin code

Revision History

Revision	Date	Major changes
1.0	2025/6/22	Release of Preliminary version.

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.